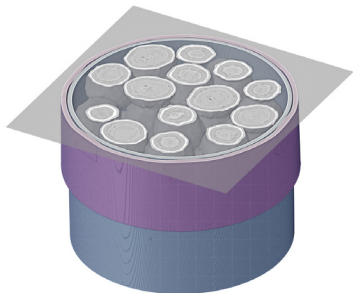


prolonged-release tablets

200 gigabyte 32-bit 3D datasets

rapid μ CT analysis

segmentation visualization reporting



XPLORAYTION GmbH

facilitates access to non-destructive rapid synchrotron-based micro computer tomography analysis at highest sensitivities and spatial resolutions. Bridging the gap between highly advanced laboratory and synchrotron-based analytics and R&D demand, we offer not just consulting services, but a comprehensive all-round package: from sample preparation and the actual measurements over data analysis and visualization to the final reporting. Through us, you gain access to state-of-the-art X-ray sources for the assessment of material composition.

XPLORAYTION offers

rapid and smooth access to **Synchrotron- μ CT analysis**

- high sample throughput: **hundreds** of samples per day
- high resolution: pixel size: 0.2 – 30 μ m
- phase contrast: for high sensitivity
- in situ time-resolved measurements in controlled liquid environments

3D characterization of tablet morphology through high-throughput **Synchrotron μ CT** with sub-micron resolution and phase contrast (e.g. pore size distribution, inclusions, coating thickness, grain boundaries, surface roughness, ...)

Additional X-ray analysis we offer

- **X-ray spectroscopy**: analysis of elemental and chemical compositions at sub-micron resolutions and sensitivities in the ppm range (e.g. elemental mapping to find contaminations, co-localization of different elements, oxidation states,...)
- **X-ray diffraction tomography** : to assess crystalline properties in 2- and 3-dimensions

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